## N-Channel Shielded Gate POWERTRENCH<sup>®</sup> MOSFET

### 80 V, 84 A, 6.7 mΩ

#### Description

This N-Channel MV MOSFET is produced using ON Semiconductor's advanced POWERTRENCH process that incorporates Shielded Gate technology. This process has been optimized to minimize on-state resistance and yet maintain superior switching performance with best in class soft body diode.

#### Features

- Shielded Gate MOSFET Technology
- Max  $r_{DS(on)} = 6.7 \text{ m}\Omega$  at  $V_{GS} = 10 \text{ V}$ ,  $I_D = 21 \text{ A}$
- Max  $r_{DS(on)} = 9.9 \text{ m}\Omega$  at  $V_{GS} = 4.5 \text{ V}$ ,  $I_D = 17 \text{ A}$
- 50% Lower Q<sub>rr</sub> than Other MOSFET Suppliers
- Lowers Switching Noise/EMI
- MSL1 Robust Package Design
- 100% UIL Tested
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

#### **Typical Applications**

- Primary DC-DC MOSFET
- Synchronous Rectifier in DC-DC and AC-DC
- Motor Drive
- Solar

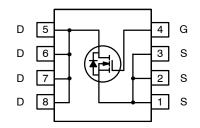


#### **ON Semiconductor®**

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V <sub>DS</sub>	r <sub>DS(on)</sub> MAX	I <sub>D MAX</sub>
80 V	$6.7~\mathrm{m}\Omega @ 10~\mathrm{V}$	84 A





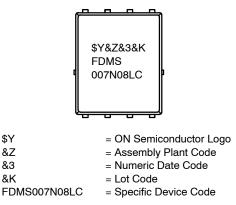


Тор

Bottom

PQFN8 5×6, 1.27P (Power 56) CASE 483AE

#### MARKING DIAGRAM



#### ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

#### **MOSFET MAXIMUM RATINGS** (T<sub>A</sub> = 25°C, Unless otherwise specified)

Symbol	Р	arameter	Ratings	Unit
V <sub>DS</sub>	Drain to Source Voltage	Itage		V
V <sub>GS</sub>	Gate to Source Voltage		±20	V
I <sub>D</sub>	Drain Current – Continuous	T <sub>C</sub> = 25°C (Note 5)	84	А
	– Continuous	T <sub>C</sub> = 100°C (Note 5)	53	1
	– Continuous	T <sub>A</sub> = 25°C (Note 1a)	14	1
	– Pulsed (Note	4)	345	1
E <sub>AS</sub>	Single Pulse Avalanche Energy (Not	e 3)	181.5	mJ
PD	Power Dissipation	$T_{C} = 25^{\circ}C$	92.6	W
	Power Dissipation	T <sub>A</sub> = 25°C (Note 1a)	2.5	1
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Terr	iperature Range	-55 to +150	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

#### THERMAL CHARACTERISTICS

Symbol	Parameter	Ratings	Unit
$R_{ extsf{ heta}JC}$	Thermal Resistance, Junction to Case	1.35	°C/W
$R_{ heta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	50	

#### PACKAGE MARKING AND ORDERING INFORMATION

Device Marking	Device	Package	Reel Size	Tape Width	Shipping (Qty / Packing) <sup>†</sup>
FDMS007N08LC	FDMS007N08LC	PQFN8 5×6 (Power 56) (Pb–Free/Halogen Free)	13″	12 mm	3000 / Tape & Reel

+For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

## **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
OFF CHARA	CTERISTICS					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250 \ \mu\text{A}, \ V_{GS} = 0 \ V$	80	-	_	V
$\frac{\Delta \text{BV}_{\text{DSS}}}{\Delta \text{T}_{\text{J}}}$	Breakdown Voltage Temperature Coefficient	$I_D = 250 \ \mu\text{A}$ , referenced to $25^{\circ}\text{C}$	-	32	Ι	mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS}$ = 64 V, $V_{GS}$ = 0 V	_	-	1	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS}=\pm 20~\text{V},~V_{DS}=0~\text{V}$	_	_	±100	μΑ

#### **ON CHARACTERISTICS**

V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS}$ = $V_{DS}$ , $I_D$ = 120 $\mu$ A	1.0	1.4	2.5	V
$\frac{\Delta {\rm V}_{\rm GS(th)}}{\Delta {\rm T}_{\rm J}}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 120 \ \mu\text{A}$ , referenced to 25°C	-	-5.6	-	mV/°C
r <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS}$ = 10 V, I <sub>D</sub> = 21 A	-	4.9	6.7	mΩ
		$V_{GS} = 4.5 \text{ V}, \text{ I}_{D} = 17 \text{ A}$	-	6.7	9.9	
		$V_{GS}$ = 10 V, I <sub>D</sub> = 21 A, T <sub>J</sub> = 125°C	-	8.5	11.6	
<b>9</b> FS	Forward Transconductance	V <sub>DD</sub> = 5 V, I <sub>D</sub> = 21 A	_	84	_	S

#### ELECTRICAL CHARACTERISTICS (T<sub>J</sub> = 25°C unless otherwise noted)

#### DYNAMIC CHARACTERISTICS

C <sub>iss</sub>	Input Capacitance	$V_{DS}$ = 40 V, $V_{GS}$ = 0 V, f = 1 MHz	-	2227	3100	pF
C <sub>oss</sub>	Output Capacitance		-	520	760	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		-	27	40	pF
R <sub>G</sub>	Gate Resistance		0.1	0.4	0.8	Ω

#### SWITCHING CHARACTERISTICS

	The Data Tree			40	04	
t <sub>d(on)</sub>	Turn-on Delay Time	$V_{DD} = 40 \text{ V}, \text{ I}_{D} = 21 \text{ A}, \text{ V}_{GS} = 10 \text{ V},$	-	10	21	ns
t <sub>r</sub>	Rise Time	$R_{GEN} = 6 \Omega$	-	3	10	
t <sub>d(off)</sub>	Turn-off Delay Time		-	38	61	
t <sub>f</sub>	Fall Time		-	8	16	
Qg	Total Gate Charge	$V_{GS}$ = 0V to 10 V, $V_{DD}$ = 40 V, $I_{D}$ = 21 A	-	33	46	nC
Qg	Total Gate Charge	$V_{GS}$ = 0V to 4.5 V, $V_{DD}$ = 40 V, $I_{D}$ = 21 A	-	16	22	nC
Q <sub>gs</sub>	Gate to Source Charge	V <sub>DD</sub> = 40 V, I <sub>D</sub> = 21 A	-	5	-	nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge	V <sub>DD</sub> = 40 V, I <sub>D</sub> = 21 A	-	4	-	nC
Q <sub>oss</sub>	Output Charge	$V_{DD}$ = 40 V, $V_{GS}$ = 0 V	-	30	-	nC
Q <sub>sync</sub>	Total Gate Charge Sync	V <sub>DS</sub> = 0 V, I <sub>D</sub> = 21 A	-	35	-	nC

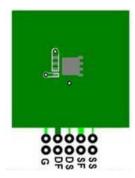
#### DRAIN-SOURCE DIODE CHARACTERISTICS

V <sub>SD</sub>	Source to Drain Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 2.1 A (Note 2)	-	0.7	1.2	V
		V <sub>GS</sub> = 0 V, I <sub>S</sub> = 21 A (Note 2)	-	0.8	1.3	V
t <sub>rr</sub>	Reverse Recovery Time	I <sub>F</sub> = 10 A, di/dt = 300 A/μs	-	18	32	ns
Q <sub>rr</sub>	Reverse Recovery Charge		-	24	28	nC
t <sub>rr</sub>	Reverse Recovery Time	$I_F = 10 \text{ A}, \text{ di/dt} = 1000 \text{ A/}\mu\text{s}$	-	13	23	ns
Q <sub>rr</sub>	Reverse Recovery Charge		-	58	92	nC

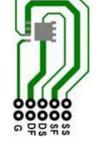
Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

#### NOTES:

1.  $R_{\theta JA}$  is determined with the device mounted on a 1 in<sup>2</sup> pad 2 oz copper pad on a 1.5 × 1.5 in. board of FR-4 material.  $R_{\theta CA}$  is determined by the user's board design.



a) 50°C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.



b) 125°C/W when mounted on a minimum pad of 2 oz copper.

- Pulse Test: Pulse Width < 300 μs, Duty cycle < 2.0%.</li>
  E<sub>AS</sub> of 181 mJ is based on starting T<sub>J</sub> = 25°C; L = 3 mH, I<sub>AS</sub> = 11 A, V<sub>DD</sub> = 80 V, V<sub>GS</sub> = 10 V. 100% tested at L = 0.1 mH, I<sub>AS</sub> = 35 A.
  Pulsed I<sub>D</sub> please refer to Fig. 11 SOA graph for more details.
  Computed continuous current limited to Max Junction Temperature only, actual continuous current will be limited by the prevaled by th
- thermal & electro-mechanical application board design.



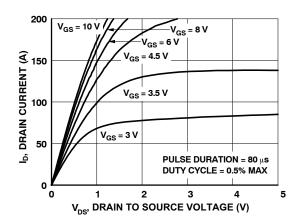
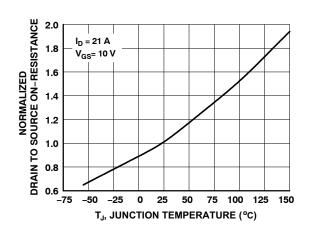


Figure 1. On Region Characteristics





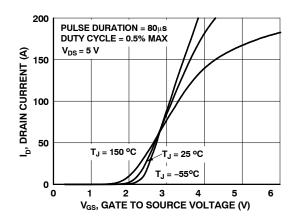


Figure 5. Transfer Characteristics

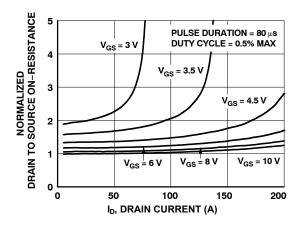


Figure 2. Normalized On–Resistance vs. Drain Current and Gate Voltage

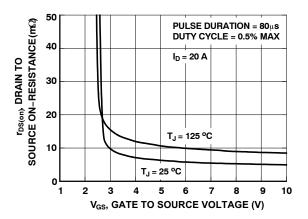


Figure 4. On-Resistance vs. Gate to Source Voltage

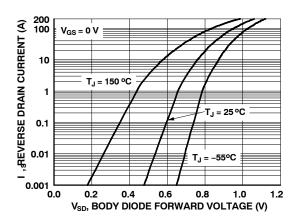


Figure 6. Source to Drain Diode Forward Voltage vs. Source Current

#### TYPICAL CHARACTERISTICS (continued)

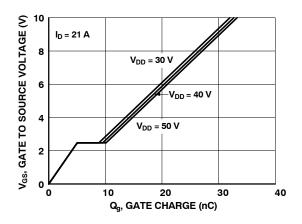


Figure 7. Gate Charge Characteristics

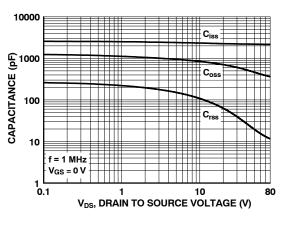
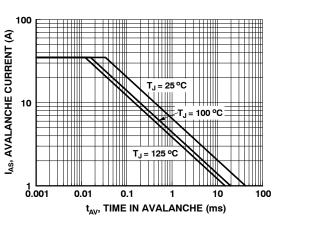


Figure 8. Capacitance vs. Drain to Source Voltage





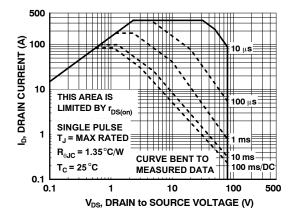


Figure 11. Forward Bias Safe Operating Area

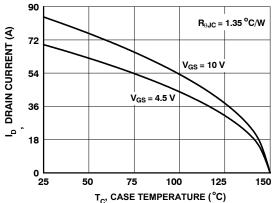


Figure 10. Maximum Continuous Drain Current vs. Case Temperature

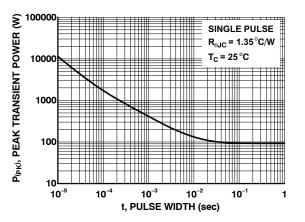


Figure 12. Single Pulse Maximum Power Dissipation

#### TYPICAL CHARACTERISTICS (continued)

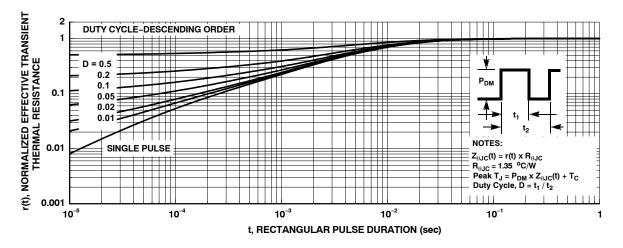


Figure 13. Junction-to-Case Transient Thermal Response Curve

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PQFN8 5X6, 1.27P CASE 483AE ISSUE C DATE 21 JAN 2022 HA D1 SEE NOTES: DETAIL B PKG В 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2009. 2. CONTROLLING DIMENSION: MILLIMETERS 3. COPLANARITY APPLIES TO THE EXPOSED PADS AS WELL AS THE TERMINALS. PKG € 4. DIMENSIONS D1 AND E1 DO NOT INCLUDE E1 MOLD FLASH, PROTRUSIONS, OR GATE BURRS. 5. SEATING PLANE IS DEFINED BY THE TERMINALS, "A1" IS DEFINED AS THE DISTANCE FROM THE SEATING PLANE TO THE LOWEST POINT ON THE PACKAGE BODY. PIN 1 6. IT IS RECOMMENDED TO HAVE NO TRACES OR OPTIONAL DRAFT AREA ANGLE MAY APPEAR VIAS WITHIN THE KEEP OUT AREA. ON FOUR SIDES TOP VIEW OF THE PACKAGE θ // 0.10 C L2 J Ť SEE DETAIL C MILLIMETERS DIM 0.08 C С MIN. NOM. MAX. A3 SEATING А 0.90 1.00 1.10 DETAIL B DETAIL C PLANE A1 0.00 0.05 SCALE: 2:1 SIDE VIEW SCALE: 2:1 0.21 0.31 0.41 b b1 0.31 0.41 0.51 5.10 0.15 0.25 0.35 A3 · 3.91 D 4.90 5.00 5.20 1.27 D1 4.80 4.90 5.00 0.77 D2 3.61 3.82 3.96 e1 Е 5.90 6.15 6.25 4.52 E1 5.70 5.80 5.90 -b1 (4X) -e-3 .75 (z) (4X) E2 3.38 3.48 3.78 6 61 E3 0.30 REF E4 0.52 REF KEEP OUT L AREA 1.27 BSC е \*\*\* 1.27 0.635 BSC **F**<sup>(e2)</sup> e/2 3.81 BSC e1 ٹر<sub>(E4)</sub> e2 0.50 REF Ŧ 0.61 (8X) E2 1.27 (F3) L 0.51 0.66 0.76 3.81 (2X L2 0.05 0.18 0.30 LAND PATTERN L4 0.34 0.44 0.54 RECOMMENDATION ل\_ <sub>(4X)</sub> 0.34 REF z \*FOR ADDITIONAL INFORMATION ON OUR θ e/2 0 -12° PB-FREE STRATEGY AND SOLDERING b (8X) DETAILS, PLEASE DOWNLOAD THE ON SEMICONDUCTOR SOLDERING AND MOUNTING TECHNIQUES REFERENCE BOTTOM VIEW MANUAL, SOLDERRM/D.

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